

American National Standard

INCITS/ISO/IEC 10373-3:2010[2011]

(ISO/IEC 10373-3:2010, IDT)

*Identification cards - Test methods - Part 3:
Integrated circuit cards with contacts and
related interface devices*

Developed by



Where IT all begins



INCITS/ISO/IEC 10373-3:2010[2011]

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Identification cards — Test methods — Part 3: Integrated circuit cards with contacts and related interface devices

Cartes d'identification — Méthodes d'essai —

*Partie 3: Cartes à circuit(s) intégré(s) à contacts et dispositifs d'interface
assimilés*

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Foreword

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International Standards are drafted in accordance with the rules given in the ISO/IEC Directives, Part 2.

The main task of the joint technical committee is to prepare International Standards. Draft International Standards adopted by the joint technical committee are circulated to national bodies for voting. Publication as an International Standard requires approval by at least 75 % of the national bodies casting a vote.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO and IEC shall not be held responsible for identifying any or all such patent rights.

ISO/IEC 10373-3 was prepared by Joint Technical Committee ISO/IEC JTC 1, *Information technology*, Subcommittee SC 17, *Cards and personal identification*.

This second edition cancels and replaces the first edition (ISO/IEC 10373-3:2001), which has been technically revised.

ISO/IEC 10373 consists of the following parts, under the general title *Identification cards — Test methods*:

- *Part 1: General characteristics*
- *Part 2: Cards with magnetic stripes*
- *Part 3: Integrated circuit cards with contacts and related interface devices*
- *Part 5: Optical memory cards*
- *Part 6: Proximity cards*
- *Part 7: Vicinity cards*
- *Part 8: USB-ICC*

The following part is under preparation:

- *Part 9: Optical memory cards: Holographic recording method*